

## IN THE U.S. PATENT AND TRADEMARK OFFICE

application of

Toshiya SHIMURA et al.

Conf. 7580

Application No. 09/973,762

Group 2643

RECEIVED

Filed October 11, 2001

Examiner B. Taylor

JUN 2 9 2004

METHOD OF MEASURING AND IMPROVING XDSL TRANSMISSION CHARACTERISTIC

**Technology Center 2600** 

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

June 28, 2004

Sir:

In compliance with Rules 1.97 and 1.98, and in ful-fillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed Form PTO-1449.

A concise explanation of the relevance of these items is that these references were cited by the Japanese Patent Office in an Official Action. A copy of the Japanese Official Action in which they were cited is attached hereto, with what is believed to be the pertinent portion enclosed in a wavy line. An English translation of the enclosed portion is also attached hereto.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION			Attorney Docket No.: 8026-1008		Application No.: 09/973,762		
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(Use several sheets if necessary)			Filing Date: October 11, 2001		Group Art Unit: 2643		
		U.S. PATEN	T DOCUMENTS			,	-
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		FOREIGN PAT	ENT DOCUMENTS			<b>-</b>	
Examiner Initial	Document Number	Date	Country	CI	ass Subclas	s Trans Yes	lation No
Tillia	WO 99/53637	10/21/1999	INTERNATIONAL			103	140
	JP 2000-13343	1/14/2000	JAPAN				
	JP 2002-511699	4/16/2002	JAPAN				
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	OTHER DOCUMEN	ITS (Including A	uthor, Title, Date, Pertine	nt Page	s, Etc.)		
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not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* Abstract provided for the Examiner's convenience